

具有 1.8V 逻辑的 TMUX7219 44V、抗闩锁、2:1 (SPDT) 精密开关

1 特性

抗闩锁效应

双电源电压范围: ±4.5V 至 ±22V • 单电源电压范围: 4.5V 至 44V

低导通电阻:2Ω

• -40°C 至 +125°C 工作温度 • 逻辑电平: 1.8V 至 VDD

• 失效防护逻辑

• 轨到轨运行

• 双向信号路径

• 先断后合开关

• ESD 保护 HBM: 2000V

2 应用

• 工厂自动化和工业控制

可编程逻辑控制器 (PLC)

• 模拟输入模块

• 半导体测试

• 交流充电(桩)站

• 超声波扫描仪

• 患者监护和诊断

• 光纤网络

• 光学测试设备

• 远程无线电单元

• 有线网络

数据采集系统

3 说明

TMUX7219 是一款具有抗闩锁效应的互补金属氧化物 半导体 (CMOS) 开关, 采用单通道 2:1 (SPDT) 配置。 此器件在双电源(±4.5V至±22V)、单电源(4.5V至 44V) 或非对称电源(例如 V_{DD} = 12V, V_{SS} = -5V) 供电时均能正常运行。TMUX7219 可在源极 (Sx) 和漏 极 (D) 引脚上支持从 V_{SS} 到 {15}VDD 范围的双向模拟 和数字信号。

可以通过控制 EN 引脚来启用或禁用 TMUX7219。当 禁用时,两个信号路径开关都关闭。当启用时,SEL 引脚可用于打开信号路径 1 (S1 至 D)或信号路径 2 (S2 至 D)。所有逻辑控制输入均支持 1.8V 到 V_{DD} 的逻辑电平,因此,当器件在有效电源电压范围内运行 时,可确保 TTL 和 CMOS 逻辑兼容性。失效防护逻辑 电路允许先在控制引脚上施加电压,然后在电源引脚上 施加电压,从而保护器件免受潜在的损害。

TMUX72xx 系列具有抗闩锁特性,可防止器件内寄生 结构之间通常由过压事件引起的大电流不良事件。闩锁 状态通常会一直持续到电源轨关闭为止,并可能导致器 件故障。抗闩锁特性使得 TMUX72xx 系列开关和多路 复用器能够在恶劣的环境中使用。

器件信息

	PP 11 1P	
器件型号	封装	封装尺寸 (标称值)
TMUX7219	VSSOP (8) (DGK)	3.00mm × 3.00mm

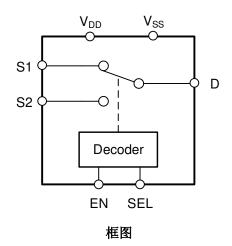




Table of Contents

1 特性	1	7.7 Charge Injection	24
 2 应用		7.8 Off Isolation	
3 说明		7.9 Crosstalk	25
4 Revision History		7.10 Bandwidth	26
5 Pin Configuration and Functions		7.11 THD + Noise	26
Specifications		7.12 Power Supply Rejection Ratio (PSRR)	27
6.1 Absolute Maximum Ratings		8 Detailed Description	
6.2 ESD Ratings		8.1 Overview	
6.3 Thermal Information		8.2 Functional Block Diagram	28
6.4 Recommended Operating Conditions		8.3 Feature Description	28
6.5 Source or Drain Continuous Current		8.4 Device Functional Modes	29
6.6 ±15 V Dual Supply: Electrical Characteristics		8.5 Truth Tables	29
6.7 ±15 V Dual Supply: Switching Characteristics		9 Application and Implementation	30
6.8 ±20 V Dual Supply: Electrical Characteristics		9.1 Application Information	30
6.9 ±20 V Dual Supply: Switching Characteristics		9.2 Typical Application	30
6.10 44 V Single Supply: Electrical Characteristic		10 Power Supply Recommendations	31
6.11 44 V Single Supply: Switching Characteristic		11 Layout	32
6.12 36 V Single Supply: Electrical Characteristic		11.1 Layout Guidelines	32
6.13 36 V Single Supply: Switching Characteristic		11.2 Layout Example	
6.14 12 V Single Supply: Electrical Characteristic		12 Device and Documentation Support	33
6.15 12 V Single Supply: Switching Characteristic		12.1 Documentation Support	33
6.16 Typical Characteristics		12.2 Receiving Notification of Documentation Updates	33
7 Parameter Measurement Information		12.3 Support Resources	
7.1 On-Resistance		12.4 Trademarks	
7.2 Off-Leakage Current		12.5 Electrostatic Discharge Caution	
7.3 On-Leakage Current		12.6 Glossary	33
7.4 Transition Time		13 Mechanical, Packaging, and Orderable	
7.5 Break-Before-Make		Information	33
7.6 t _{ON(EN)} and t _{OFF(EN)}	24		
` '			

4 Revision History

注:以前版本的页码可能与当前版本的页码不同

С	hanges from Revision * (January 2019) to Revision A (December 2020)	Page
•	Updated Figure 6-9 Leakage Current vs Temperature	16
•	Updated Figure 6-15 Charge Injection vs Source Voltage - Dual Supplies (Source Side)	16

Submit Document Feedback



5 Pin Configuration and Functions

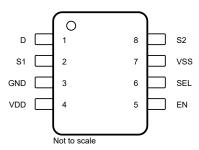


图 5-1. DGK Package 8-Pin VSSOP Top View

表 5-1. Pin Functions

NAME	NO.	TYPE(1)	DESCRIPTION ⁽²⁾
D	1	I/O	Drain pin. Can be an input or output.
S1	2	I/O	Source pin 1. Can be an input or output.
GND	3	Р	Ground (0 V) reference
V _{DD}	4	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V_{DD} and GND.
EN	5	I	Active high logic enable, has internal pull-up resistor. When this pin is low, all switches are turned off. When this pin is high, the SEL logic input determine which switch is turned on.
SEL	6	I	Logic control input, has internal pull-down resistor. Controls the switch connection as shown in † 8.5.
V _{SS}	7	Р	Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V _{SS} and GND.
S2	8	I/O	Source pin 2. Can be an input or output.

- (1) I = input, O = output, I/O = input and output, P = power.
- (2) Refer to 节 8.4 for what to do with unused pins.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1) (2) (3)

		MIN	MAX	UNIT
V _{DD} - V _{SS}			48	V
V_{DD}	Supply voltage	- 0.5	48	V
V _{SS}		- 48	0.5	V
V _{SEL} or V _{EN}	Logic control input pin voltage (SEL, EN) ⁽⁴⁾	- 0.5	48	V
I _{SEL} or I _{EN}	Logic control input pin current (SEL, EN) ⁽⁴⁾	- 30	30	mA
V _S or V _D	Source or drain voltage (Sx, D) ⁽⁴⁾	V _{SS} - 0.5	V _{DD} +0.5	V
I _{IK}	Diode clamp current ⁽⁴⁾	- 30	30	mA
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)	I _{DC} + 10 %	(5)	mA
T _A	Ambient temperature	- 55	135	°C
T _{stg}	Storage temperature	- 65	150	°C
T _J	Junction temperature		140	°C

- Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum.
- (3) All voltages are with respect to ground, unless otherwise specified.
- 4) Pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.
- (5) Refer to Source or Drain Continuous Current table for IDC specifications.

6.2 ESD Ratings

				VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins ⁽¹⁾	±2000	V	
	(ESD)		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±500	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Thermal Information

		TMUX7219	
	THERMAL METRIC(1)	DGK (VSSOP)	UNIT
		8 PINS	
R ₀ JA	Junction-to-ambient thermal resistance	152.1	°C/W
R _{θ JC(top)}	Junction-to-case (top) thermal resistance	48.4	°C/W
R ₀ JB	Junction-to-board thermal resistance	73.2	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	4.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	71.8	°C/W
R _{θ JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	°C/W

 For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

Product Folder Links: TMUX7219



6.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V _{DD} - V _{SS} (1)	Power supply voltage differential	4.5	44	V
V _{DD}	Positive power supply voltage	4.5	44	V
V _S or V _D	Signal path input/output voltage (source or drain pin) (Sx, D)	V _{SS}	V_{DD}	V
V _{SEL} or V _{EN}	Address or enable pin voltage	0	44	V
Is or I _{D (CONT)}	Source or drain continuous current (Sx, D)		I _{DC} (2)	mA
T _A	Ambient temperature	- 40	125	°C

- (1) V_{DD} and V_{SS} can be any value as long as 4.5 V \leq (V_{DD} V_{SS}) \leq 44 V, and the minimum V_{DD} is met.
- (2) Refer to Source or Drain Continuous Current table for I_{DC} specifications.

6.5 Source or Drain Continuous Current

at supply voltage of V_{DD} ± 10%, V_{SS} ± 10 % (unless otherwise noted)

CONTINI	UOUS CURRENT PER CHANNEL (I _{DC})	T _△ = 25°C	T _Δ = 85°C	T = 425°C	UNIT
PACKAGE	TEST CONDITIONS	1A - 25 C	1A - 65 C	T _A = 125°C	UNIT
	+44 V Single Supply ⁽¹⁾	330	210	120	mA
	±15 V Dual Supply	330	210	120	mA
DGK (VSSOP)	+12 V Single Supply	240	160	100	mA
	±5 V Dual Supply	240	160	100	mA
	+5 V Single Supply	180	120	80	mA

(1) Specified for nominal supply voltage only.



6.6 ±15 V Dual Supply: Electrical Characteristics

 V_{DD} = +15 V ± 10%, V_{SS} = -15 V ±10%, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +15 V, V_{SS} = -15 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V _S = -10 V to +10 V	25°C		2.1	2.9	Ω
R _{ON}	On-resistance	_D = - 10 mA	- 40°C to +85°C			3.8	Ω
A RON RON FLAT RON DRIFT IS(OFF) IS(ON) ID(ON) LOGIC INF VIH VIL IIH		Refer to On-Resistance	- 40°C to +125°C			4.5	Ω
		V _S = -10 V to +10 V	25°C		0.05	0.25	Ω
△ R _{ON}	On-resistance mismatch between channels	$I_D = -10 \text{ mA}$	- 40°C to +85°C			0.3	Ω
	Chamicis	Refer to On-Resistance	- 40°C to +125°C			0.35	Ω
		V _S = -10 V to +10 V	25°C		0.5	0.6	Ω
R _{ON FLAT}	On-resistance flatness	$I_S = -10 \text{ mA}$	- 40°C to +85°C			0.7	Ω
R _{ON DRIFT}		Refer to On-Resistance	- 40°C to +125°C			0.85	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 0 V, I _S = - 10 mA Refer to On-Resistance	- 40°C to +125°C		0.009		Ω/°C
		V _{DD} = 16.5 V, V _{SS} = -16.5 V	25°C	- 1	3 15 0.08 1.8	nA	
lovers	Source off leakage current ⁽¹⁾	Switch state is off V _S = +10 V / - 10 V V _D = -10 V / + 10 V Refer to Off-Leakage Current	- 40°C to +85°C	- 3		3	nA
'S(OFF)			- 40°C to +125°C	- 15		15	nA
	Drain off leakage current ⁽¹⁾	V_{DD} = 16.5 V, V_{SS} = -16.5 V Switch state is off V_{S} = +10 V / -10 V V_{D} = -10 V / +10 V Refer to Off-Leakage Current	25°C	- 1.8	0.08	1.8	nA
I			- 40°C to +85°C	- 5		5	nA
'D(OFF)			- 40°C to +125°C	- 26		26	nA
		V_{DD} = 16.5 V, V_{SS} = -16.5 V Switch state is on V_S = V_D = ±10 V Refer to On-Leakage Current	25°C	- 1.5	0.05	1.5	nA
I _{S(ON)}	Channel on leakage current ⁽²⁾		- 40°C to +85°C	- 3.5		3.5	nA
'D(ON)			- 40°C to +125°C	- 18		18	nA
LOGIC IN	PUTS (SEL / EN pins)			1			
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	1.2	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.95	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	SUPPLY	1	1	1		l	
			25°C		25	40	μΑ
I _{DD}	V _{DD} supply current	V_{DD} = 16.5 V, V_{SS} = -16.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			50	μΑ
		Logic inputs – v v, 5 v, or V _{DD}	- 40°C to +125°C			80	μΑ
			25°C		3	10	μΑ
I _{SS}	V _{SS} supply current	V_{DD} = 16.5 V, V_{SS} = $-$ 16.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			20	μΑ
			- 40°C to +125°C			40	μΑ
	I .	1		1			

- (1) When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.
- (2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

Submit Document Feedback



6.7 ±15 V Dual Supply: Switching Characteristics

 V_{DD} = +15 V ± 10%, V_{SS} = - 15 V ±10%, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +15 V, V_{SS} = - 15 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 10 V	25°C		120	175	ns
t _{TRAN}	Transition time from control input	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C			190	ns
		Refer to Transition Time	- 40°C to +125°C			210	ns
		V _S = 10 V	25°C		80	170	ns
	Turn-on time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			185	ns
		Time	- 40°C to +125°C			200	ns
		V _S = 10 V	25°C		110	180	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			195	ns
		Time	- 40°C to +125°C			210	ns
		V _S = 10 V,	25°C		50		ns
t _{BBM}	Break-before-make time delay	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
			25°C		0.15 1 1 140 - 11	ms	
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 100ns R _I = 300 Ω , C _I = 35 pF	- 40°C to +85°C			1	ms
	(100	333 ss, 3 <u>L</u> 33 p.	- 40°C to +125°C		1 0.15 1 1 140	ms	
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		140		ps
Q _{INJ}	Charge injection	V _D = 0 V, C _L = 1 nF Refer to Charge Injection	25°C		- 11		рС
O _{ISO}	Off-isolation	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 0 \ V$, $f = 100 \ kHz$ Refer to Off Isolation	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, $f = 1 MHz$ Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 100 kHz Refer to Crosstalk	25°C		- 92		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, $f = 1MHz$ Refer to Crosstalk	25°C		- 75		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$ Refer to Bandwidth	25°C		40		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1 MHz	25°C		- 0.2		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 10 M Ω , C_L = 5 pF, f = 1 MHz Refer to AC PSRR	25°C		- 40		dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} = 15 V, V_{BIAS} = 0 V R_L = 10 k Ω , C_L = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	25°C	().0005		%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C		36		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C		49		pF
C _{S(ON)} , C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C		150		pF



6.8 ±20 V Dual Supply: Electrical Characteristics

 V_{DD} = +20 V ± 10%, V_{SS} = - 20 V ±10%, GND = 0 V (unless otherwise noted) Tvpical at V_{DD} = +20 V, V_{SS} = - 20 V, T_{A} = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V _S = - 15 V to +15 V	25°C		1.9	2.7	Ω
R _{ON}	On-resistance	$I_D = -10 \text{ mA}$	- 40°C to +85°C			3.7	Ω
A RON RON FLAT RON DRIFT IS(OFF) IS(OFF) LOGIC INP VIH VIL IIH IIL		Refer to On-Resistance	- 40°C to +125°C			4.4	Ω
		V _S = -15 V to +15 V	25°C		0.04	0.22	Ω
△ R _{ON}	On-resistance mismatch between channels	$I_D = -10 \text{ mA}$	- 40°C to +85°C			0.28	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.28	Ω
		V _S = -15 V to +15 V	25°C		0.3	0.75	Ω
R _{ON FLAT}	On-resistance flatness	$I_S = -10 \text{ mA}$	- 40°C to +85°C			0.9	Ω
R _{ON DRIFT}		Refer to On-Resistance	- 40°C to +125°C			1.2	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 0 V, I _S = - 10 mA Refer to On-Resistance	- 40°C to +125°C		0.008		Ω/°C
		V _{DD} = 22 V, V _{SS} = -22 V	25°C	- 2	- 4 - 24 - 2.5 0.1	2	nA
lavore:	Source off leakage current ⁽¹⁾	Switch state is off V _S = +15 V / - 15 V V _D = -15 V / + 15 V Refer to Off-Leakage Current	- 40°C to +85°C	- 4		4	nA
'S(OFF)			- 40°C to +125°C	- 24		24	nA
	Drain off leakage current ⁽¹⁾	V_{DD} = 22 V, V_{SS} = -22 V Switch state is off V_{S} = +15 V / -15 V V_{D} = -15 V / +15 V Refer to Off-Leakage Current	25°C	- 2.5	0.1	2.5	nA
I			- 40°C to +85°C	- 8		8	nA
'D(OFF)			- 40°C to +125°C	- 44		44	nA
		V_{DD} = 22 V, V_{SS} = -22 V Switch state is on V_{S} = V_{D} = ±15 V Refer to On-Leakage Current	25°C	- 2	0.1	2	nA
I _{S(ON)}	Channel on leakage current ⁽²⁾		- 40°C to +85°C	- 5		5	nA
ID(ON)			- 40°C to +125°C	- 29		29	nA
LOGIC IN	PUTS (SEL / EN pins)			1			
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.4	1.2	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.98	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	SUPPLY	I	1	1			
			25°C		26	39	μA
I _{DD}	V _{DD} supply current	V_{DD} = 22 V, V_{SS} = -22 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			43	μΑ
		Logic inputs = 0 v, 5 v, or V _{DD}	- 40°C to +125°C			48	μΑ
			25°C		4	6	μA
I _{SS}	V _{SS} supply current	V_{DD} = 22 V, V_{SS} = -22 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			7	μΑ
	33 117		- 40°C to +125°C			8	μA

- (1) When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.
- (2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

Submit Document Feedback



6.9 ±20 V Dual Supply: Switching Characteristics

 V_{DD} = +20 V ± 10%, V_{SS} = - 20 V ±10%, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +20 V, V_{SS} = - 20 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 10 V	25°C		100	190	ns
t _{TRAN}	Transition time from control input	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C			200	ns
		Refer to Transition Time	- 40°C to +125°C			220	ns
		V _S = 10 V	25°C		80	180	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			200	ns
		Time	- 40°C to +125°C			220	ns
		V _S = 10 V	25°C		90	180	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			200	ns
		Time	- 40°C to +125°C			220	ns
		V _S = 10 V,	25°C		60		ns
t _{BBM}	Break-before-make time delay	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
			25°C		0.17		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 100ns R _I = 300 Ω, C _I = 35 pF	- 40°C to +85°C			1	ms
	(333 a, 3 <u>2</u> 33 p.	- 40°C to +125°C			1	ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		122		ps
Q _{INJ}	Charge injection	V _D = 0 V, C _L = 1 nF Refer to Charge Injection	25°C	- 14.8			рС
O _{ISO}	Off-isolation	$R_L = 50~\Omega$, $C_L = 5~pF$ $V_S = 0~V$, $f = 100~kHz$ Refer to Off Isolation	25°C	- 75			dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, $f = 1 MHz$ Refer to Off Isolation	25°C	- 55			dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 100 kHz Refer to Crosstalk	25°C		- 92		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1MHz Refer to Crosstalk	25°C		- 74		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, Refer to Bandwidth	25°C		38		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1 MHz	25°C	-	0.16		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 10 M Ω , C_L = 5 pF, f = 1 MHz Refer to AC PSRR	25°C	- 38			dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} = 20 V, V_{BIAS} = 0 V R_L = 10 k Ω , C_L = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	25°C	0.0005			%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C		33		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C		44		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C		148		pF



6.10 44 V Single Supply: Electrical Characteristics

 V_{DD} = +44 V, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +44 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V _S = 0 V to 40 V	25°C		2.3	2.8	Ω
R _{ON}	On-resistance	I _D = - 10 mA	- 40°C to +85°C			3.6	Ω
		Refer to On-Resistance	- 40°C to +125°C			4.3	Ω
		V _S = 0 V to 40 V	25°C		0.1	0.2	Ω
ΔR_{ON}	On-resistance mismatch between channels	I _D = - 10 mA	- 40°C to +85°C			0.3	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.35	Ω
		V _S = 0 V to 40 V	25°C		0.2	1	Ω
R _{ON FLAT}	On-resistance flatness	I _D = - 10 mA	- 40°C to +85°C			1.3	Ω
		Refer to On-Resistance	- 40°C to +125°C			1.5	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 22 V, I _S = -10 mA Refer to On-Resistance	- 40°C to +125°C		0.02		Ω/°C
		V _{DD} = 44 V, V _{SS} = 0 V	25°C	- 5	0.05	5	nA
I _{S(OFF)} Sou	Source off leakage current ⁽¹⁾	Switch state is off V _S = 40 V / 1 V	- 40°C to +85°C	- 10		10	nA
		V _D = 1 V / 40 V Refer to Off-Leakage Current	- 40°C to +125°C	- 35		35	nA
		V _{DD} = 44 V, V _{SS} = 0 V	25°C	- 8	0.05	8	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off V _S = 40 V / 1 V	- 40°C to +85°C	- 12		12	nA
_(-,-,	-	V _D = 1 V / 40 V Refer to Off-Leakage Current	- 40°C to +125°C	- 70		70	nA
		$V_{DD} = 44 \text{ V}, V_{SS} = 0 \text{ V}$	25°C	- 8	0.05	8	nA
I _{S(ON)} I _{D(ON)}	Channel on leakage current ⁽²⁾	Switch state is on $V_S = V_D = 40 \text{ V or } 1 \text{ V}$	- 40°C to +85°C	- 10		10	nA
D(014)		Refer to On-Leakage Current	- 40°C to +125°C	- 45		45	nA
LOGIC IN	PUTS (SEL / EN pins)		•				
V_{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V_{IL}	Logic voltage low		- 40°C to +125°C	0		8.0	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	1.2	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.95	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	SUPPLY						
		V - 44 V V - 0 V	25°C		17	50	μA
I_{DD}	V _{DD} supply current	V_{DD} = 44 V, V_{SS} = 0 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			60	μΑ
			- 40°C to +125°C			75	μΑ

- (1) When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.
- (2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

6.11 44 V Single Supply: Switching Characteristics

 V_{DD} = +44 V, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +44 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
t _{TRAN}		$V_S = 18 \text{ V}$ $R_L = 300 \Omega$, $C_L = 35 \text{ pF}$	25°C		100	185	ns
	Transition time from control input		- 40°C to +85°C			200	ns
			- 40°C to +125°C			220	ns

Submit Document Feedback



6.11 44 V Single Supply: Switching Characteristics (continued)

 V_{DD} = +44 V, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +44 V, V_{SS} = 0 V, T_A = 25 $^{\circ}$ C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 18 V	25°C		80	180	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			200	ns
		Time	- 40°C to +125°C			220	ns
		V _S = 18 V	25°C		90	180	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			200	ns
		Time	- 40°C to +125°C			220	ns
		V _S = 18 V,	25°C		45		ns
t _{BBM}	Break-before-make time delay	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
			25°C		0.14		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 100ns R _I = 300 Ω , C _I = 35 pF	- 40°C to +85°C			1	ms
(Ob to surput)		11. 000 tr , OL 00 pr	- 40°C to +125°C			1	ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		185		ps
Q _{INJ}	Charge injection	V _D = 22 V, C _L = 1 nF Refer to Charge Injection	25°C		- 16.5		рС
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Off Isolation	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 1 MHz$ Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 100 kHz Refer to Crosstalk	25°C		- 92		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1MHz Refer to Crosstalk	25°C		- 75		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$ Refer to Bandwidth	25°C		37		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C		- 0.18		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 10 M Ω , C_L = 5 pF, f = 1 MHz Refer to AC PSRR	25°C		- 39		dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} = 22 V, V_{BIAS} = 22 V R_L = 10 k Ω , C_L = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	L = 5 pF, Hz 25°C 0.0003			%	
C _{S(OFF)}	Source off capacitance	V _S = 22 V, f = 1 MHz	25°C		33		pF
C _{D(OFF)}	Drain off capacitance	V _S = 22 V, f = 1 MHz	25°C		45		pF
C _{S(ON)} , C _{D(ON)}	On capacitance	V _S = 22 V, f = 1 MHz	25°C		148		pF



6.12 36 V Single Supply: Electrical Characteristics

 V_{DD} = +36 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +36 V, V_{SS} = 0 V, T_A = 25 $^{\circ}\mathrm{C}$ (unless otherwise noted)

V _A	SWITCH Analog signal range						
	Analog signal range						
R _{ON}			- 40°C to +125°C	V _{SS}		V_{DD}	V
R _{ON}		V _S = 0 V to 30 V	25°C		2.5	3.5	Ω
	On-resistance	I _D = - 10 mA	- 40°C to +85°C			4.5	Ω
		Refer to On-Resistance	- 40°C to +125°C			5	Ω
		V _S = 0 V to 30 V	25°C		0.1	0.2	Ω
∆ R _{ON}	On-resistance mismatch between channels	$I_D = -10 \text{ mA}$	- 40°C to +85°C			0.25	Ω
	CHAINICIS	Refer to On-Resistance	- 40°C to +125°C			0.3	Ω
		V _S = 0 V to 30 V	25°C		0.3	1	Ω
R _{ON FLAT}	On-resistance flatness	I _S = -10 mA	- 40°C to +85°C			1.5	Ω
		Refer to On-Resistance	- 40°C to +125°C			2	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 18 V, I _S = -10 mA Refer to On-Resistance	- 40°C to +125°C		0.02		Ω/°C
		V _{DD} = 39.6 V, V _{SS} = 0 V	25°C	- 0.25	0.05	0.25	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = 30 V / 1 V	- 40°C to +85°C	- 3		3	nA
'S(OFF)		V _D = 1 V / 30 V Refer to Off-Leakage Current	- 40°C to +125°C	- 26		26	nA
		V _{DD} = 39.6 V, V _{SS} = 0 V	25°C	- 1	0.05	1	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off V _S = 30 V / 1 V	- 40°C to +85°C	- 5		5	nA
·D(OFF)		V _D = 1 V / 30 V Refer to Off-Leakage Current	- 40°C to +125°C	- 50		50	nA
		V _{DD} = 39.6 V, V _{SS} = 0 V	25°C	- 0.4	0.05	0.4	nA
$I_{S(ON)}$ $I_{D(ON)}$	Channel on leakage current ⁽²⁾	Switch state is on $V_S = V_D = 30 \text{ V or } 1 \text{ V}$	- 40°C to +85°C	- 4.5		4.5	nA
·D(ON)		Refer to On-Leakage Current	- 40°C to +125°C	- 32		32	nA
LOGIC IN	PUTS (SEL / EN pins)					'	
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		8.0	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.4	1.2	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.98	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	SUPPLY	1	1				
			25°C		28	50	μΑ
I _{DD}	V _{DD} supply current	$V_{DD} = 39.6 \text{ V}, V_{SS} = 0 \text{ V}$ Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			60	μΑ
			- 40°C to +125°C			70	μΑ

⁽¹⁾ When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

Submit Document Feedback

⁽²⁾ When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.



6.13 36 V Single Supply: Switching Characteristics

 V_{DD} = +36 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +36 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 18 V	25°C		100	170	ns
t _{TRAN}	Transition time from control input	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C			185	ns
		Refer to Transition Time	- 40°C to +125°C			200	ns
		V _S = 18 V	25°C		80	180	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C			190	ns
(=:-,		Refer to Turn-on and Turn-off Time	- 40°C to +125°C			200	ns
		V _S = 18 V	25°C		90	180	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \ pF$	- 40°C to +85°C			195	ns
,		Refer to Turn-on and Turn-off Time	- 40°C to +125°C			200	ns
		V - 10 V	25°C		60		ns
t _{BBM}	Break-before-make time delay	$V_S = 18 \text{ V},$ $R_L = 300 \Omega, C_L = 35 \text{ pF}$	- 40°C to +85°C	1			ns
22	•	Refer to Break-Before-Make	- 40°C to +125°C	1			ns
			25°C		0.14		ms
T _{ON (VDD)}	Device turn on time	V _{DD} rise time = 100ns	- 40°C to +85°C			1	ms
ON (VDD)	(V _{DD} to output)	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +125°C			1	ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		200		ps
Q _{INJ}	Charge injection	V _D = 18 V, C _L = 1 nF Refer to Charge Injection	25°C		- 13		pC
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Off Isolation	25°C	- 75			dB
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz V_S = 6 V Solution 25°C V_S = 55			dB		
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 100 kHz Refer to Crosstalk	25°C		- 95		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1MHz Refer to Crosstalk	25°C		- 70		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, Refer to Bandwidth	25°C		38		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C		- 0.19		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 10 M Ω , C_L = 5 pF, f = 1 MHz Refer to AC PSRR	25°C	- 38			dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} =18 V, V_{BIAS} = 18 V R_{L} = 10 k Ω , C_{L} = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise			%		
C _{S(OFF)}	Source off capacitance	V _S = 18 V, f = 1 MHz	25°C		34		pF
C _{D(OFF)}	Drain off capacitance	V _S = 18 V, f = 1 MHz	25°C		47		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 18 V, f = 1 MHz	25°C		148		pF



6.14 12 V Single Supply: Electrical Characteristics

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH					-	
		V _S = 0 V to 10 V	25°C		4.6	6	Ω
R _{ON}	On-resistance	I _D = - 10 mA	- 40°C to +85°C			7.5	Ω
		Refer to On-Resistance	- 40°C to +125°C			8.6	Ω
		V _S = 0 V to 10 V	25°C		0.08	0.25	Ω
ΔR_{ON}	On-resistance mismatch between channels	I _D = - 10 mA	- 40°C to +85°C			0.35	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.4	Ω
		V _S = 0 V to 10 V	25°C		1.2	1.9	Ω
R _{ON FLAT}	On-resistance flatness	I _S = - 10 mA	- 40°C to +85°C			2.2	Ω
		Refer to On-Resistance	- 40°C to +125°C			2.5	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 6 V, I _S = -10 mA Refer to On-Resistance	- 40°C to +125°C		0.02		Ω/°C
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 1	0.05	1	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = 10 V / 1 V	- 40°C to +85°C	- 2		2	nΑ
		V _D = 1 V / 10 V Refer to Off-Leakage Current	- 40°C to +125°C	- 12		12	nA
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 1.5	0.05	1.5	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off V _S = 10 V / 1 V	- 40°C to +85°C	- 3		3	nA
_(-,-,		V _D = 1 V / 10 V Refer to Off-Leakage Current	- 40°C to +125°C	- 23		23	nA
		$V_{DD} = 13.2 \text{ V}, V_{SS} = 0 \text{ V}$	25°C	- 1	0.05	1	nΑ
I _{S(ON)} I _{D(ON)}	Channel on leakage current ⁽²⁾	Switch state is on $V_S = V_D = 10 \text{ V}$ or 1 V	- 40°C to +85°C	- 3		3	nA
<i>D</i> (014)		Refer to On-Leakage Current	- 40°C to +125°C	- 15		15	nΑ
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		8.0	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	1.2	μΑ
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.96	- 0.005		μΑ
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	SUPPLY						
		V = 42 2 V V = 0 V	25°C		10	35	μΑ
I_{DD}	V _{DD} supply current	V_{DD} = 13.2 V, V_{SS} = 0 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			45	μA
			- 40°C to +125°C			55	μΑ

- (1) When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.
- (2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

6.15 12 V Single Supply: Switching Characteristics

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_{A} = 25°C (unless otherwise noted)

. , , ,	Typical at V _{DD} 12 V, V _{SS} 0 V, I _A 20 0 (alliese strict these fields)										
PARAMETER		AMETER TEST CONDITIONS		MIN	TYP	MAX	UNIT				
		$V_S = 8 \text{ V}$ $R_L = 300 \Omega$, $C_L = 35 \text{ pF}$ Refer to Transition Time	25°C		180	200	ns				
t _{TRAN}	Transition time from control input		- 40°C to +85°C			220	ns				
			- 40°C to +125°C			250	ns				

Submit Document Feedback



6.15 12 V Single Supply: Switching Characteristics (continued)

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TA	MIN	TYP	MAX	UNIT
		V _S = 8 V	25°C		120	200	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$ Refer to Turn-on and Turn-off	- 40°C to +85°C			220	ns
		Time	- 40°C to +125°C			250	ns
		V _S = 8 V	25°C		130	220	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C			250	ns
- ()		Refer to Turn-on and Turn-off Time	- 40°C to +125°C			280	ns
		V _S = 8 V,	25°C		60		ns
t _{BBM}	Break-before-make time delay	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
			25°C		0.17		ms
T _{ON (VDD)}	Device turn on time	V _{DD} rise time = 100ns	- 40°C to +85°C			1	ms
(,	(V _{DD} to output)	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +125°C			1	ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		250		ps
		$V_D = 6 \text{ V}, C_L = 1 \text{ nF}$	05%0				
Q _{INJ}	Charge injection	Refer to Charge Injection			- 6		рС
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Charge Injection	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 1 MHz$ Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Crosstalk	25°C		- 92		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 1MHz$ Refer to Crosstalk	25°C		- 85		dB
BW	- 3dB Bandwidth	R_L = 50 Ω , C_L = 5 pF V_S = 6 V Refer to Bandwidth	25°C		42		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C		- 0.3		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 10 M Ω , C_L = 5 pF, f = 1 MHz Refer to AC PSRR	25°C		- 42		dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} = 6 V, V_{BIAS} = 6 V R_L = 10 k Ω , C_L = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	25°C	25°C 0.0009			%
C _{S(OFF)}	Source off capacitance	V _S = 6 V, f = 1 MHz	25°C		44		pF
C _{D(OFF)}	Drain off capacitance	V _S = 6 V, f = 1 MHz	25°C		62		pF
C _{S(ON)} , C _{D(ON)}	On capacitance	V _S = 6 V, f = 1 MHz	25°C		155		pF



6.16 Typical Characteristics

at T_A = 25°C

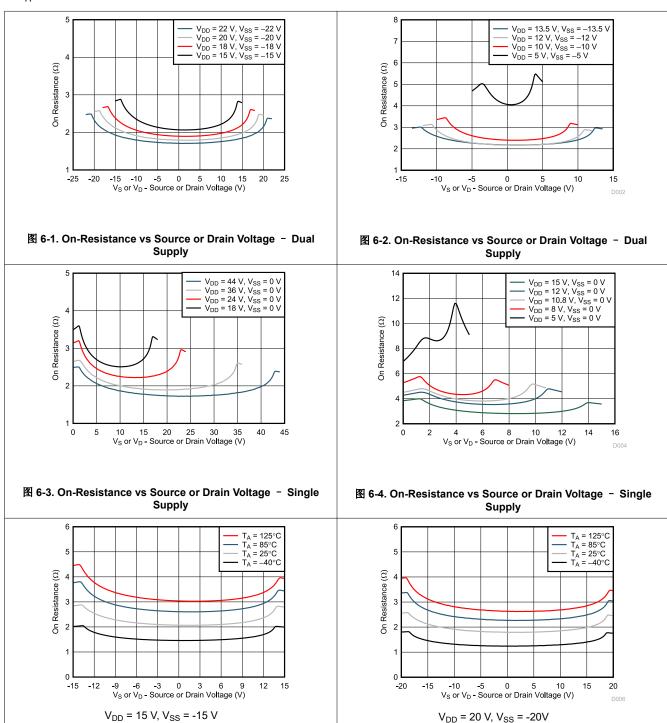
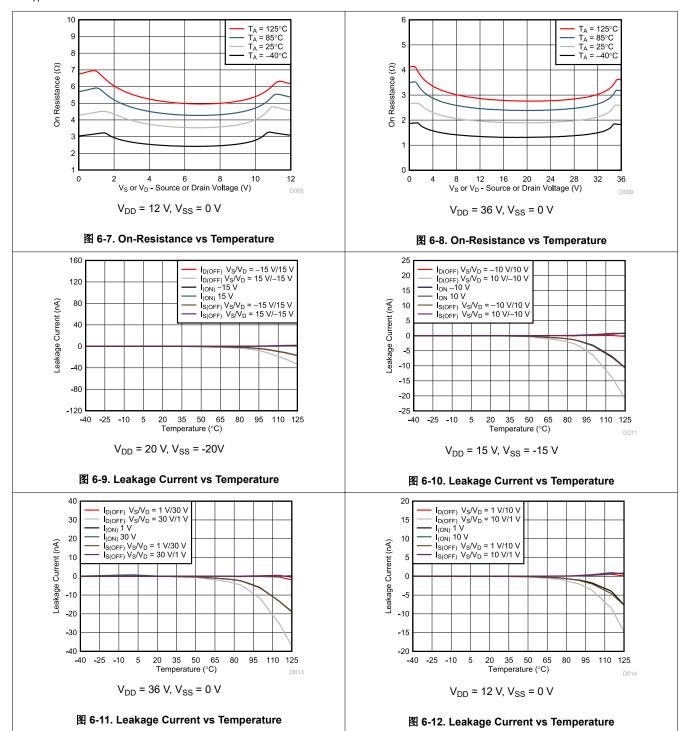


图 6-5. On-Resistance vs Temperature

图 6-6. On-Resistance vs Temperature



at $T_A = 25$ °C





at T_A = 25°C

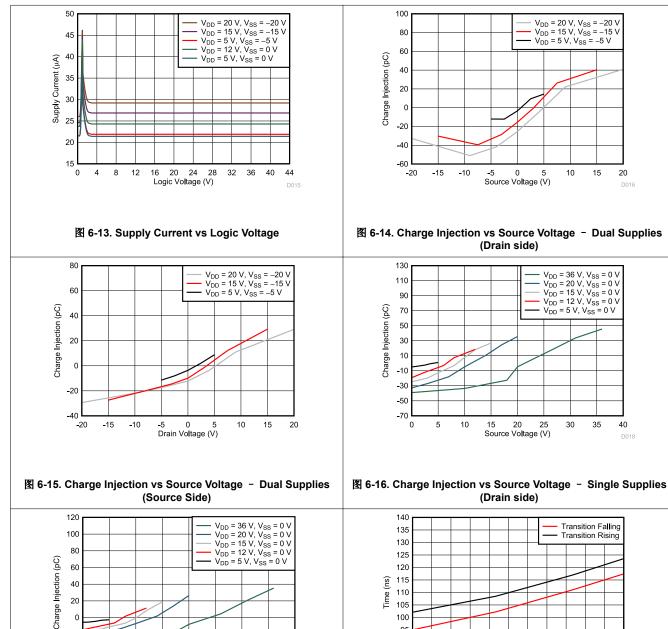


图 6-17. Charge Injection vs Source Voltage - Single Supplies (Source Side)

20 25

Drain Voltage (V)

30 35 40

10

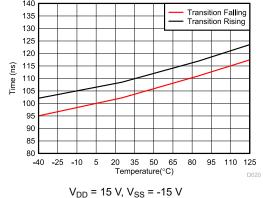


图 6-18. T_{TRANSITION} vs Temperature

Submit Document Feedback

20

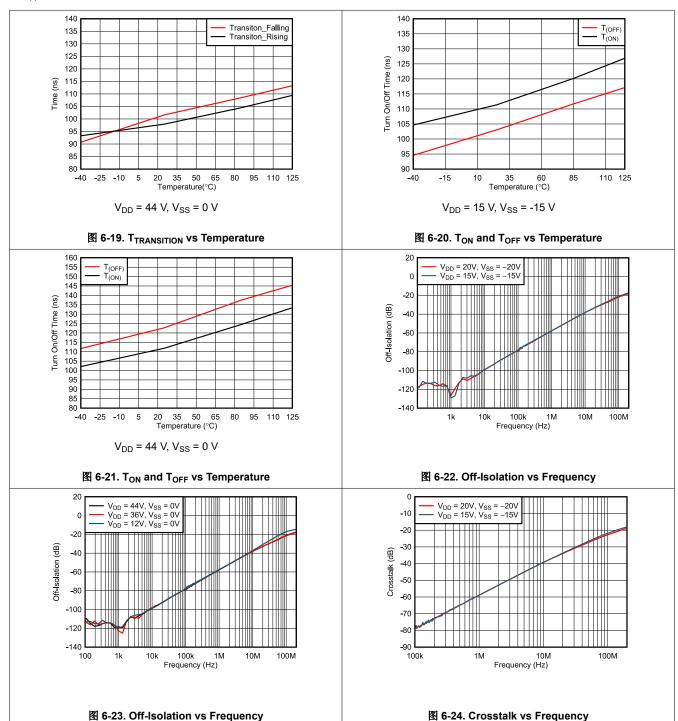
-20

-40

0 5

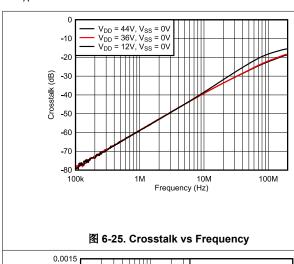


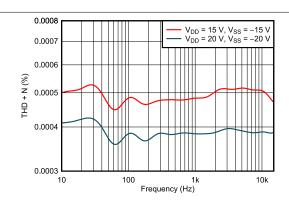
at $T_A = 25$ °C





at T_A = 25°C





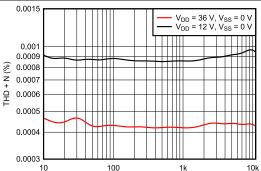


图 6-26. THD+N vs Frequency (Dual Supplies)

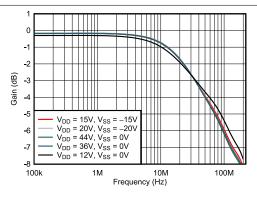


图 6-27. THD+N vs Frequency (Single Supplies)

Frequency (Hz)

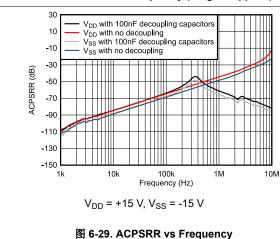


图 6-28. On Response vs Frequency

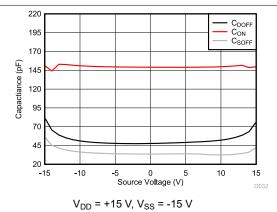
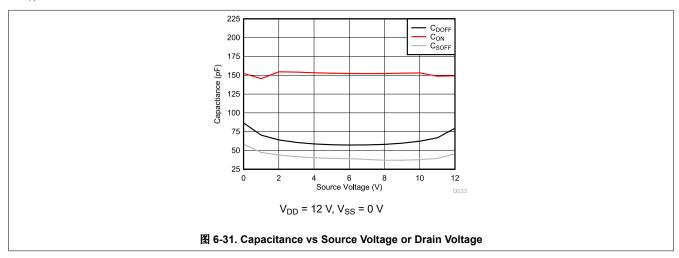


图 6-30. Capacitance vs Source Voltage or Drain Voltage

Submit Document Feedback



at $T_A = 25$ °C





7 Parameter Measurement Information

7.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. 3 7-1 shows the measurement setup used to measure R_{ON} . Voltage (V) and current (I_{SD}) are measured using the following setup, where R_{ON} is computed as $R_{ON} = V / I_{SD}$:

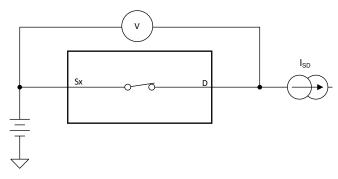


图 7-1. On-Resistance

7.2 Off-Leakage Current

There are two types of leakage currents associated with a switch during the off state:

- 1. Source off-leakage current.
- 2. Drain off-leakage current.

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol $I_{D(OFF)}$.

图 7-2 shows the setup used to measure both off-leakage currents.

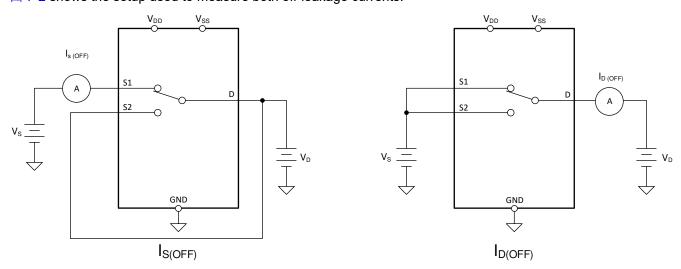


图 7-2. Off-Leakage Measurement Setup

Submit Document Feedback



7.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol $I_{S(ON)}$.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol $I_{D(ON)}$.

Either the source pin or drain pin is left floating during the measurement. $\boxed{8}$ 7-3 shows the circuit used for measuring the on-leakage current, denoted by $I_{S(ON)}$ or $I_{D(ON)}$.

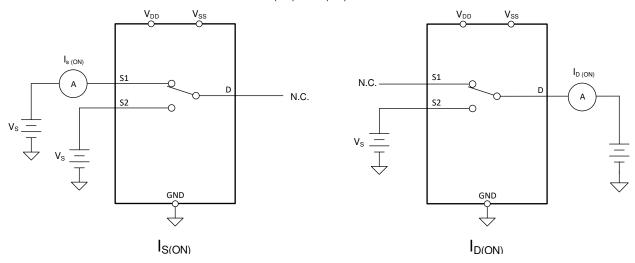


图 7-3. On-Leakage Measurement Setup

7.4 Transition Time

Transition time is defined as the time taken by the output of the device to rise or fall 10% after the address signal has risen or fallen past the logic threshold. The 10% transition measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. 🛭 7-4 shows the setup used to measure transition time, denoted by the symbol transition.

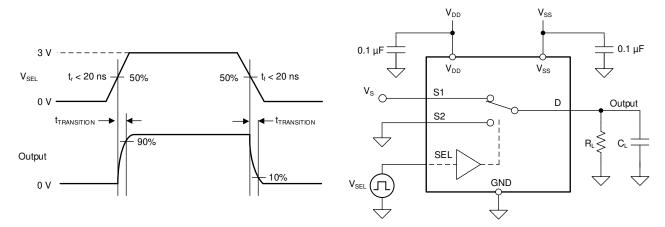


图 7-4. Transition-Time Measurement Setup



7.5 Break-Before-Make

Break-before-make delay is a safety feature that prevents two inputs from connecting when the device is switching. The output first breaks from the on-state switch before making the connection with the next on-state switch. The time delay between the *break* and the *make* is known as break-before-make delay.

7-5 shows the setup used to measure break-before-make delay, denoted by the symbol topen(BBM).

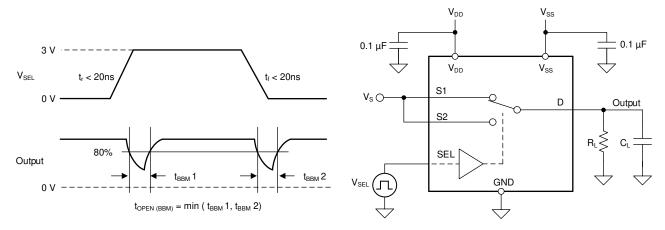


图 7-5. Break-Before-Make Delay Measurement Setup

7.6 t_{ON(EN)} and t_{OFF(EN)}

Turn-on time is defined as the time taken by the output of the device to rise to 10% after the enable has risen past the logic threshold. The 10% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. $\boxed{8}$ 7-6 shows the setup used to measure turn-on time, denoted by the symbol $t_{ON(FN)}$.

Turn-off time is defined as the time taken by the output of the device to fall to 90% after the enable has fallen past the logic threshold. The 90% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. $\boxed{8}$ 7-6 shows the setup used to measure turn-off time, denoted by the symbol $t_{OFF(EN)}$.

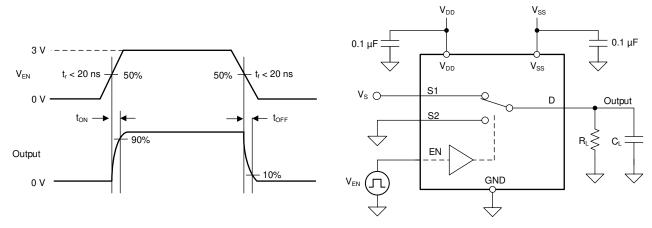


图 7-6. Turn-On and Turn-Off Time Measurement Setup

7.7 Charge Injection

The TMUX7219 has a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is

Product Folder Links: TMUX7219



denoted by the symbol Q_C . \boxtimes 7-7 shows the setup used to measure charge injection from source (Sx) to drain (D).

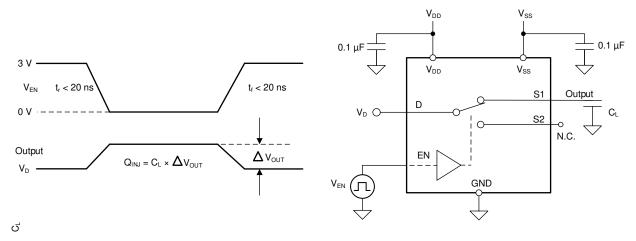


图 7-7. Charge-Injection Measurement Setup

7.8 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (D) of the device when a signal is applied to the source pin (Sx) of an off-channel. 🗵 7-8 shows the setup used to measure, and the equation used to calculate off isolation.

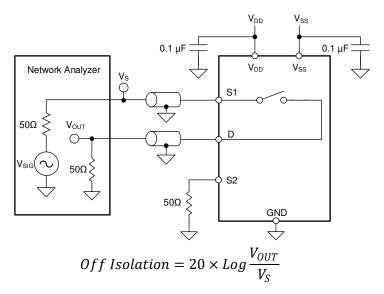


图 7-8. Off Isolation Measurement Setup

Off Isolation =
$$20 \cdot Log\left(\frac{V_{OUT}}{V_{S}}\right)$$
 (1)

7.9 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. 37-9 shows the setup used to measure, and the equation used to calculate crosstalk.



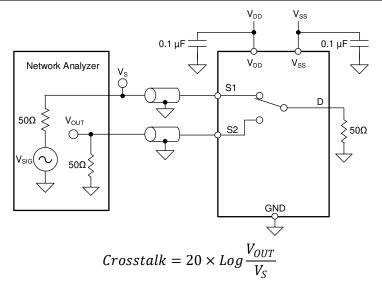


图 7-9. Crosstalk Measurement Setup

7.10 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (D) of the device.

7-10 shows the setup used to measure bandwidth.

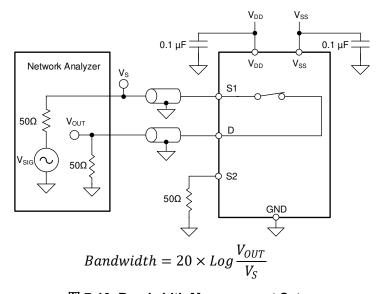


图 7-10. Bandwidth Measurement Setup

7.11 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the mux output. The on-resistance of the device varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD+N.

Submit Document Feedback



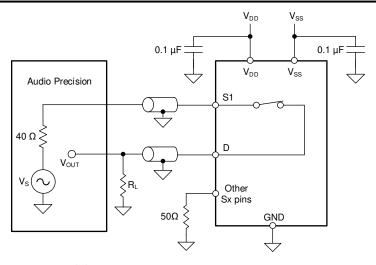


图 7-11. THD+N Measurement Setup

7.12 Power Supply Rejection Ratio (PSRR)

PSRR measures the ability of a device to prevent noise and spurious signals that appear on the supply voltage pin from coupling to the output of the switch. The DC voltage on the device supply is modulated by a sine wave of 620 mV $_{\rm PP}$. The ratio of the amplitude of signal on the output to the amplitude of the modulated signal is the AC PSRR. A high ratio represents a high degree of tolerance to supply rail variation.

§ 6-29 shows how the de-coupling capacitors reduce high frequency noise on the supply pins. This helps stabilize the supply and immediately filter as much of the supply noise as possible.

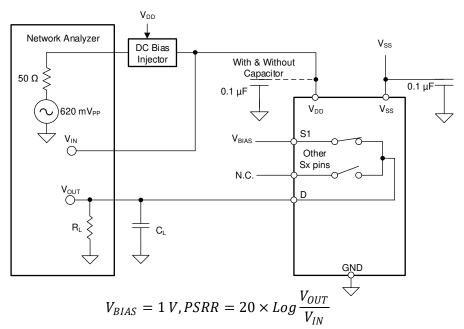


图 7-12. AC PSRR Measurement Setup



8 Detailed Description

8.1 Overview

The TMUX6219 is an 2:1, 1-channel switch. Each input is turned on or turned off based on the state of the select line and enable pin.

8.2 Functional Block Diagram

The TMUX7219 is an 2:1, 1-channel switch. Each input is turned on or turned off based on the state of the select line and enable pin.

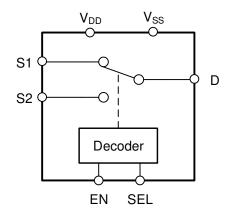


图 8-1. TMUX7219 Functional Block Diagram

8.3 Feature Description

8.3.1 Bidirectional Operation

The TMUX7219 conducts equally well from source (Sx) to drain (Dx) or from drain (Dx) to source (Sx). Each channel has very similar characteristics in both directions and supports both analog and digital signals.

8.3.2 Rail-to-Rail Operation

The valid signal path input and output voltage for TMUX7219 ranges from V_{SS} to V_{DD} .

8.3.3 1.8 V Logic Compatible Inputs

The TMUX7219 has 1.8 V logic compatible control for all logic control inputs. 1.8 V logic level inputs allows the device to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and BOM cost. For more information on 1.8 V logic implementations refer to Simplifying Design with 1.8 V logic Muxes and Switches.

8.3.4 Fail-Safe Logic

The TMUX7219 supports Fail-Safe Logic on the control input pins (EN, SEL) allowing for operation up to 44 V above V_{SS}, regardless of the state of the supply pins. This feature allows voltages on the control pins to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the logic input pins of the TMUX7219 to be ramped to +44 V while V_{DD} and V_{SS} = 0 V. The logic control inputs are protected against positive faults of up to +44 V in powered-off condition, but do not offer protection against negative overvoltage conditions.

8.3.5 Latch-Up Immune

Latch-Up is a condition where a low impedance path is created between a supply pin and ground. This condition is caused by a trigger (current injection or overvoltage), but once activated, the low impedance path remains even after the trigger is no longer present. This low impedance path may cause system upset or catastrophic damage due to excessive current levels. The Latch-Up condition typically requires a power cycle to eliminate the low impedance path.

Product Folder Links: TMUX7219



The TMUX72xx family of devices are constructed on Silicon on Insulator (SOI) based process where an oxide layer is added between the PMOS and NMOS transistor of each CMOS switch to prevent parasitic structures from forming. The oxide layer is also known as an insulating trench and prevents triggering of latch up events due to overvoltage or current injections. The latch-up immunity feature allows the TMUX72xx family of switches and multiplexers to be used in harsh environments.

8.4 Device Functional Modes

When the EN pin of the TMUX7219 is pulled high, one of the switches is closed based on the state of the SEL pin. When the EN pin is pulled low, both of the switches are in an open state regardless of the state of the SEL pin. The control pins can be as high as 44 V.

The TMUX7219 can be operated without any external components except for the supply decoupling capacitors. Unused logic control pins must be tied to GND or V_{DD} in order to ensure the device does not consume additional current as highlighted in *Implications of Slow or Floating CMOS Inputs*. Unused signal path inputs (S1, S2, or D) should be connected to GND.

8.5 Truth Tables

表 8-1 show the truth tables for the TMUX7219.

表 8-1. TMUX7219 Truth Table

EN	SEL	Selected Source Connected To Drain (D) Pin
0	X ⁽¹⁾	All sources are off (HI-Z)
1	0	S1
1	1	S2

(1) X denotes don't care.



9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

TMUX7219 is part of the precision switches and multiplexers family of devices. TMUX7219 offers low RON, low on and off leakage currents and ultra-low charge injection performance. These properties make TMUX7219 ideal for implementing high precision industrial systems requiring selection of one of two inputs or outputs.

9.2 Typical Application

9.2.1 Power Amplifier Gate Driver

One application of the TMUX7219 is for input control of a power amplifier gate driver. Utilizing a switch allows a system to control when the DAC is connected to the power amplifier, and can stop biasing the power amplifier by switching the gate to V_{SS} . The wide dual supply range of ± 4.5 V to ± 18 V allows the switch to work with GaN power amplifiers and the wide single supply range 4.5 V to 36 V works well with LDMOS power amplifiers.

⊠ 9-1 shows the TMUX7219 configured for control of the power amplifier gate driver in GaN application.

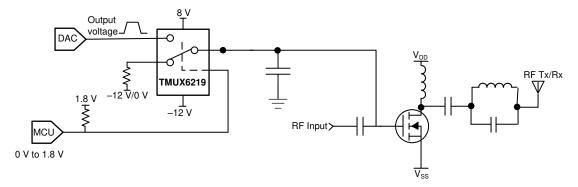


图 9-1. Power Amplifier Gate Driver

9.2.1.1 Design Requirements

For this design example, use the parameters listed in 表 9-1.

表 9-1. Design Parameters

PARAMETERS	VAL	UES
PARAMETERS	GAN application	LDMOS application
Supply (V _{DD})	8 V	5 V
Supply (V _{SS})	-12 V	0 V
MUX I/O signal range	-12 V to 8 V (Rail-to-Rail)	0 V to 5 V (Rail-to-Rail)
Control logic thresholds	1.8 V compatiable (up to V _{DD})	1.8 V compatiable (up to V _{DD})
EN	EN pulled high to enable the switch	EN pulled high to enable the switch

Product Folder Links: TMUX7219



9.2.1.2 Detailed Design Procedure

The application shown in \boxtimes 9-1 demonstrates how to toggle between the DAC output and low signal voltage for control of a GaN power amplifier using a single control input. The DAC output is utilized to bias the gate of the power amplifier and can be disconnected from the circuit using the select pin of the switch. The TMUX7219 can support 1.8 V logic signals on the control input, allowing the device to interface with low logic controls of an FPGA or MCU. The TMUX7219 can be operated without any external components except for the supply decoupling capacitors. The select pin has an internal pull-down resistor to prevent floating input logic. All inputs to the switch must fall within the recommend operating conditions of the TMUX7219 including signal range and continuous current. For this design with a positive supply of 8 V on V_{DD} , and negative supply of -12 V on V_{SS} , the signal range can be 8 V to -12 V. The max continuous current (I_{DC}) can be up to 330 mA as shown in \dagger 6.4 for wide-range current measurement.

10 Power Supply Recommendations

The TMUX7219 operates across a wide supply range of of ± 4.5 V to ± 22 V (4.5 V to 44 V in single-supply mode). The device also perform well with asymmetrical supplies such as V_{DD} = 12 V and V_{SS} = -5 V.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the supply rails to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1 μ F to 10 μ F at both the V_{DD} and V_{SS} pins to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground planes. Always ensure the ground (GND) connection is established before supplies are ramped.



11 Layout

11.1 Layout Guidelines

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self – inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners.

11-1 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

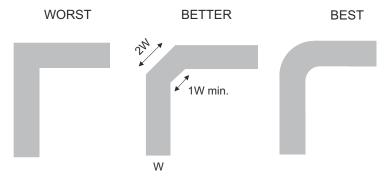


图 11-1. Trace Example

Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

- Decouple the supply pins with a 0.1-µF and 1 µF capacitor, placed lowest value capacitor as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the supply voltage.
- · Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.
- Using multiple vias in parallel will lower the overall inductance and is beneficial for connection to ground planes.

11.2 Layout Example

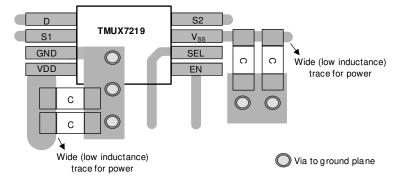


图 11-2. TMUX7219 Layout Example

Product Folder Links: TMUX7219



12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

Texas Instruments, Eliminate Power Sequencing with Powered-off Protection Signal Switches.

Texas Instruments, Improve Stability Issues with Low CON Multiplexers.

Texas Instruments, QFN/SON PCB Attachment.

Texas Instruments, Quad Flatpack No-Lead Logic Packages.

Texas Instruments, Simplifying Design with 1.8 V logic Muxes and Switches.

Texas Instruments, System-Level Protection for High-Voltage Analog Multiplexers.

Texas Instruments, True Differential, 4 x 2 MUX, Analog Front End, Simultaneous-Sampling ADC Circuit.

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

12.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

重要声明和免责声明

TI 提供技术和可靠性数据(包括数据表)、设计资源(包括参考设计)、应用或其他设计建议、网络工具、安全信息和其他资源,不保证没有瑕疵且不做出任何明示或暗示的担保,包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将独自承担以下全部责任:(1) 针对您的应用选择合适的 TI 产品,(2) 设计、验证并测试您的应用,(3) 确保您的应用满足相应标准以及任何其他安全、安保或其他要求。这些资源如有变更,恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的应用。严禁对这些资源进行其他复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务,TI 对此概不负责。

TI 提供的产品受 TI 的销售条款 () 或 TI.com.cn 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

邮寄地址:Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2020,德州仪器 (TI) 公司



PACKAGE OPTION ADDENDUM

30-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TMUX7219DGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	X219	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

DGK (S-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



DGK (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



重要声明和免责声明

TI 提供技术和可靠性数据(包括数据表)、设计资源(包括参考设计)、应用或其他设计建议、网络工具、安全信息和其他资源,不保证没有瑕疵且不做出任何明示或暗示的担保,包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任:(1) 针对您的应用选择合适的 TI 产品,(2) 设计、验证并测试您的应用,(3) 确保您的应用满足相应标准以及任何其他安全、安保或其他要求。这些资源如有变更,恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的应用。严禁对这些资源进行其他复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务,TI 对此概不负责。

TI 提供的产品受 TI 的销售条款 (https://www.ti.com.cn/zh-cn/legal/termsofsale.html) 或 ti.com.cn 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

邮寄地址:上海市浦东新区世纪大道 1568 号中建大厦 32 楼,邮政编码:200122 Copyright © 2021 德州仪器半导体技术(上海)有限公司